

# SPT IGBT Module

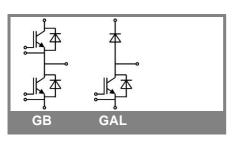
### SKM 300GB128D SKM 300GAL128D

#### **Features**

- Homogeneous Si
- SPT = Soft-Punch-Through technology
- V<sub>CEsat</sub> with positive temperature coefficient
- High short circuit capability, self limiting to 6 x I<sub>c</sub>

### **Typical Applications**

- AC inverter drives
- UPS
- Electronic welders at f<sub>sw</sub> up to 20 kHz



<b>Absolute Maximum Ratings</b> T <sub>c</sub> = 25 °C, unless otherwise specified					
Symbol	Conditions		Values	Units	
IGBT				•	
$V_{CES}$	$T_j = 25  ^{\circ}\text{C}$ $T_i = 150  ^{\circ}\text{C}$		1200	V	
I <sub>C</sub>	T <sub>j</sub> = 150 °C	T <sub>c</sub> = 25 °C	370	Α	
		T <sub>c</sub> = 80 °C	265	Α	
I <sub>CRM</sub>	I <sub>CRM</sub> =2xI <sub>Cnom</sub>		400	Α	
$V_{GES}$			± 20	V	
t <sub>psc</sub>	$V_{CC}$ = 600 V; $V_{GE} \le 20$ V; $V_{CES} < 1200$ V	T <sub>j</sub> = 125 °C	10	μs	
Inverse D	iode				
I <sub>F</sub>	T <sub>j</sub> = 150 °C	$T_{case}$ = 25 °C	260	Α	
		T <sub>case</sub> = 80 °C	180	Α	
I <sub>FRM</sub>	I <sub>FRM</sub> =2xI <sub>Fnom</sub>		400	Α	
I <sub>FSM</sub>	t <sub>p</sub> = 10 ms; sin.	T <sub>j</sub> = 150 °C	1800	Α	
Freewhee	ling Diode			•	
I <sub>F</sub>	T <sub>j</sub> = 150 °C	$T_{case}$ = 25 °C	260	Α	
		T <sub>case</sub> = 80 °C	180	Α	
I <sub>FRM</sub>	I <sub>FRM</sub> =2xI <sub>Fnom</sub>		400	Α	
I <sub>FSM</sub>	t <sub>p</sub> = 10 ms; sin.	T <sub>j</sub> = 150 °C	1800	Α	
Module					
$I_{t(RMS)}$			500	Α	
T <sub>vj</sub>			- 40+ 150	°C	
T <sub>stg</sub>			- 40+ 125	°C	
V <sub>isol</sub>	AC, 1 min.		4000	V	

Characteristics $T_c =$			25 °C, unless otherwise specified			
Symbol	Conditions		min.	typ.	max.	Units
IGBT						
$V_{GE(th)}$	$V_{GE} = V_{CE}$ , $I_C = 8 \text{ mA}$		4,5	5,5	6,5	V
I <sub>CES</sub>	$V_{GE} = 0 V, V_{CE} = V_{CES}$	$T_j = 25 ^{\circ}\text{C}$ $T_i = 25 ^{\circ}\text{C}$		0,2	0,6	mA
V <sub>CE0</sub>		T <sub>j</sub> = 25 °C		1	1,15	V
		T <sub>j</sub> = 125 °C		0,9	1,05	V
r <sub>CE</sub>	V <sub>GE</sub> = 15 V	T <sub>j</sub> = 25°C		4,5	6	mΩ
		T <sub>j</sub> = 125°C		6	7,5	mΩ
V <sub>CE(sat)</sub>	I <sub>Cnom</sub> = 200 A, V <sub>GE</sub> = 15 V	T <sub>j</sub> = 25°C <sub>chiplev.</sub>		1,9	2,35	V
		$T_j = 125^{\circ}C_{chiplev}$		2,1	2,55	V
C <sub>ies</sub>				17		nF
C <sub>oes</sub>	$V_{CE} = 25, V_{GE} = 0 V$	f = 1 MHz		2		nF
C <sub>res</sub>				1,9		nF
$Q_G$	V <sub>GE</sub> = -8V - +20V			2400		nC
R <sub>Gint</sub>	T <sub>j</sub> = 25 °C			2		Ω
t <sub>d(on)</sub>				170		ns
t <sub>r</sub> E <sub>on</sub>	$R_{Gon} = 5 \Omega$	V <sub>CC</sub> = 600V		55		ns
E <sub>on</sub>		I <sub>Cnom</sub> = 200A		22		mJ
<sup>L</sup> d(off)	$R_{Goff} = 5 \Omega$	T <sub>j</sub> = 125 °C		660		ns
t <sub>f</sub>		$V_{GE} = \pm 15V$		60		ns
E <sub>ff</sub>		L <sub>s</sub> = 20 nH		22		mJ
R <sub>th(j-c)</sub>	per IGBT				0,085	K/W



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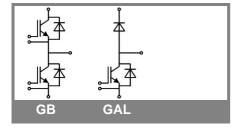
#### **Typical Applications**

- AC inverter drives
- UPS
- Electronic welders at f<sub>sw</sub> up to 20 kHz

Character	ristics						
Symbol	Conditions		min.	typ.	max.	Units	
Inverse Diode							
$V_F = V_{EC}$	$I_{Fnom}$ = 200 A; $V_{GE}$ = 0 V	$T_j = 25  ^{\circ}C_{\text{chiplev.}}$		2	2,5	V	
		$T_j = 125  ^{\circ}C_{chiplev.}$		1,8		V	
$V_{F0}$		T <sub>j</sub> = 25 °C		1,1	1,2	V	
r <sub>F</sub>		T <sub>j</sub> = 25 °C		4,5	6,5	mΩ	
I <sub>RRM</sub>	I <sub>Fnom</sub> = 200 A	T <sub>j</sub> = 125 °C		280		Α	
$Q_{rr}$	di/dt = 6300 A/μs	$L_S = 20 \text{ nH}$		33		μC	
E <sub>rr</sub>	$V_{GE} = -15 \text{ V}; V_{CC} = 600 \text{ V}$			11		mJ	
$R_{th(j-c)D}$	per diode				0,18	K/W	
FWD							
$V_F = V_{EC}$	$I_{Fnom}$ = 200 A; $V_{GE}$ = 0 V	$T_j = 25  ^{\circ}C_{\text{chiplev.}}$		2	2,5	V	
		$T_j = 125  ^{\circ}C_{\text{chiplev.}}$		1,8		V	
$V_{F0}$		$T_j = 25 \degree C$ $T_j = 25 \degree C$		1,1	1,2	V	
r <sub>F</sub>		T <sub>j</sub> = 25 °C		4,5	6,5	V	
I <sub>RRM</sub>	I <sub>Fnom</sub> = 200 A	T <sub>j</sub> = 25 °C		280		Α	
Q <sub>rr</sub>	di/dt = 6300 A/μs	L <sub>S</sub> = 20 nH		33		μC	
E <sub>rr</sub>	$V_{GE} = -15 \text{ V}; V_{CC} = 600 \text{ V}$			11		mJ	
$R_{th(j-c)FD}$	per diode				0,18	K/W	
Module							
L <sub>CE</sub>				15	20	nH	
R <sub>CC'+EE'</sub>	res., terminal-chip	T <sub>case</sub> = 25 °C		0,35		mΩ	
		T <sub>case</sub> = 125 °C		0,5		mΩ	
R <sub>th(c-s)</sub>	per module				0,038	K/W	
M <sub>s</sub>	to heat sink M6		3		5	Nm	
M <sub>t</sub>	to terminals M6		2,5		5	Nm	
w					325	g	

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

This technical information specifies semiconductor devices but promises no characteristics. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.





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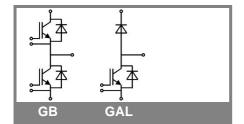
<b>Features</b>
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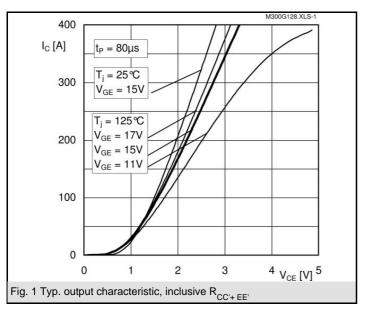
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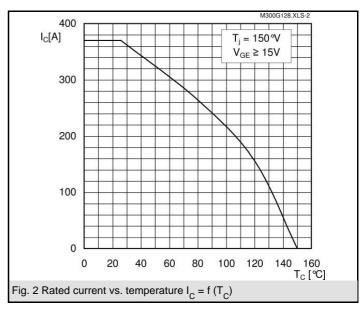
### **Typical Applications**

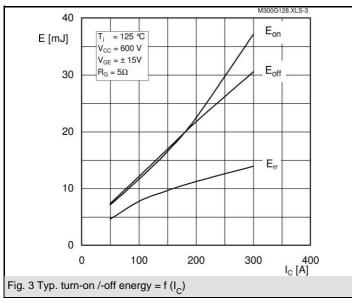
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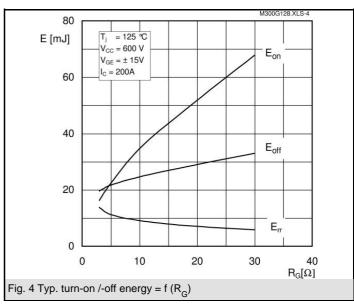
Z <sub>th</sub>			
Symbol	Conditions	Values	Units
Z <sub>th(i,o)</sub>			•
Z R <sub>i</sub>	i = 1	55	mk/W
$R_i$	i = 2	26	mk/W
R <sub>i</sub>	i = 3	3,5	mk/W
$R_{i}$	i = 4	0,5	mk/W
tau <sub>i</sub>	i = 1	0,04	s
tau <sub>i</sub>	i = 2	0,189	s
tau <sub>i</sub>	i = 3	0,0017	s
tau <sub>i</sub>	i = 4	0,003	s
Z <sub>th(j-c)D</sub>			_
R <sub>i</sub>	i = 1	120	mk/W
$R_i$	i = 2	48	mk/W
$R_{i}$	i = 3	10	mk/W
$R_{i}$	i = 4	2	mk/W
tau <sub>i</sub>	i = 1	0,0727	s
tau <sub>i</sub>	i = 2	0,006	s
tau <sub>i</sub>	i = 3	0,0078	s
tau <sub>i</sub>	i = 4	0,0002	s

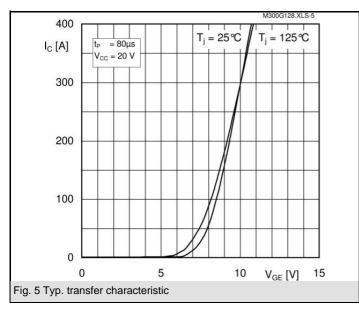


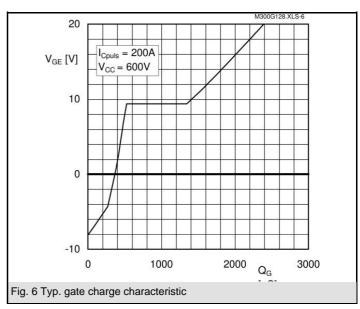


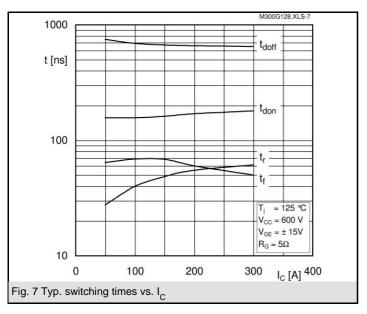


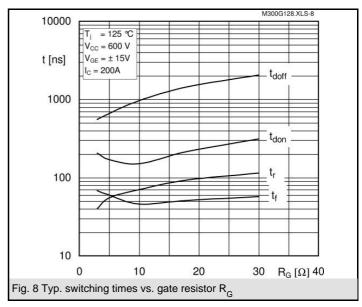


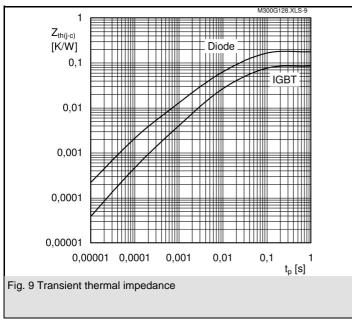


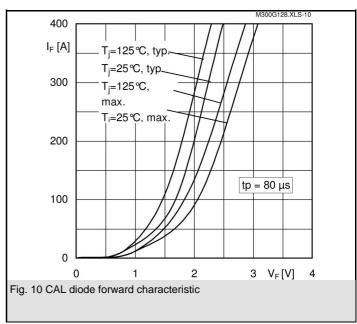


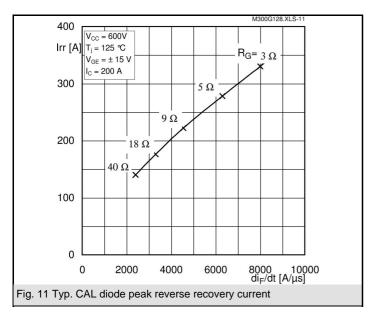


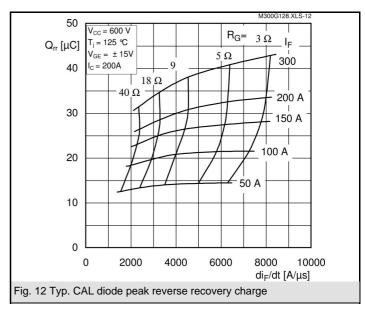


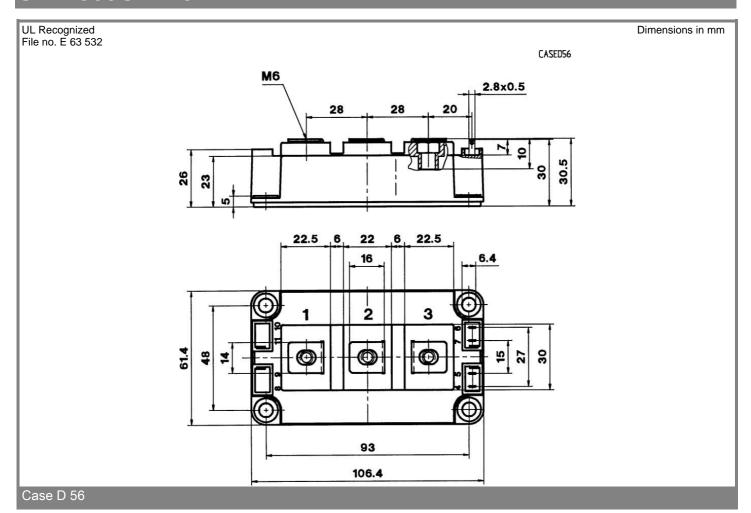


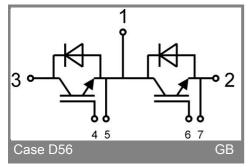


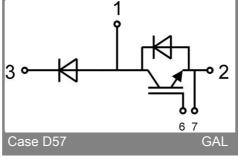












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